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Sheet	1	of	1
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Application Number	10/763,401
Filing Date	01/23/2004
First Named Inventor	Stevan Homing
Art Unit	2881
Examiner Name	Hashmi, Zia R.
Attorney Docket Number	12671-016001

[illegible]

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Country Code*	Number *Kind Code* (if known)				
Yes	B1	GB	2353632 A	02/28/2001	Brüker Daltonik GmbH		

**Examiner
Signature**

Zia R. HASIMI

Date _____

Considered

11/28/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.¹ Applicant's unique citation designation number (optional).² See Kinda Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

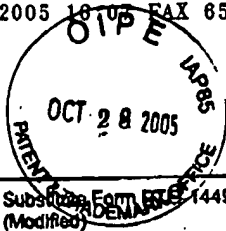
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Sheet 1 of 1

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12671-016001	Application No. 10/763,401
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Stevan Horning et al.	
		Filing Date January 23, 2004	Group Art Unit 2881

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>JS</i>	AA	5,739,530	04/14/1998	Franzen et al.			
<i>JS</i>	AB	5,179,278	01/12/1993	Douglas			
<i>JS</i>	AC	5,572,022	11/5/1996	Schwartz et al.			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>JS</i>	AD	GB 2353632	2/28/2001	United Kingdom				
	AE							
	AF							
	AG							
	AH							

Other Documents (Include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>JS</i>	AI	A. N. Krutchinsky, et al., "Collisional Damping Interface for an Electrospray Ionization Time-of-Flight Mass Spectrometer", <u>J. American Society for Mass Spectrometry</u> , 9:569-579 (1998)
<i>JS</i>	AJ	Jean H. Futrell, "Development of tandem mass spectrometry: one perspective," <u>International Journal of Mass Spectrometry</u> , 200:495-508 (2000)
	AK	
	AL	

Examiner Signature <i>Zia R. NASHU</i>	Date Considered <i>11/28/05</i>
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Substitute Disclosure Form (PTO-1449)